IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

LI et al   Atty. Ref.:   36-1901

Serial No. 10/535,634   TC/A.U.:   2613

Filed: May 20, 2005   Examiner: Unknown

For: METHOD AND SYSTEM FOR GENERATING PANORAMIC
IMAGES FROM VIDEO SEQUENCES

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June 16, 2006

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Further to the Information Disclosure Statement filed October 13, 2005, the

remainder of the missing documents from the listed attached to the Information

Disclosure Statement have now been obtained and are attached together with a further

PTO-1449.

Consideration of each reference and return of an initialed copy of the attached

form signifying same is requested.

Respectfully submitted,

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ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /J.P./

INFORMATION DISCLOSURE CITATION	ATTY. DOCKET NO.	SERIAL NO.
	36-1901	10/535,634

	APPLICANT
(Use several sheets if necessary)	LI et al

FILING DATE	TC/A.U.
May 20, 2006	2613

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO

OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

/J.P./	Hampel et al, ?The Approach Based on Influence Functions, ROBUST STATISTICS, John Wiley & Sons Inc., 1986
/J.P./	Huber, ROBUST STATISTICS, John Wiley & Sons, 1981
/J.P./	Meer et al., "Robust Regression Methods for Computer Vision: A Review, International Journal of Computer Vision, 6(1):59-70, 1991
/J.P./	Meer et al., "robust Computer Vision: An Interdisciplinary Challenge, COMPUTER VISION AND IMAGE UNDERSTANDING, 78:1-7, 2000
/J.P./	Meng et al, "CVEPS:A Compressed Video Editing and Parsing System", In ACM MULTIMEDIA, 1996

*Examiner	/James Pontius/	Date Considered	06/15/2009

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /J.P./